## Applicant(s)/Patent Under Application/Control No. Reexamination 09/848,777 AUDEH ET AL. **Notice of References Cited** Art Unit Examiner Page 1 of 1 1641 Kartic Padmanabhan **U.S. PATENT DOCUMENTS** Document Number Date Classification Name Country Code-Number-Kind Code MM-YYYY Grieve et al. 435/7.22 05-2002 US-6,391,569 Α US-В С US-US-D Ε US-F US-US-G US-Н US-US-J Κ US-US-L US-М FOREIGN PATENT DOCUMENTS Document Number Date Classification Country Name Country Code-Number-Kind Code MM-YYYY Ν 0 Р Q R S Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U ٧ W Х

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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